

# FCC Test Report FCC ID:2AELAONEGLASS

**Product:** Smartphone

Trade Name: OWN

Model Number: One Glass

Serial Model: N/A

Report No.: NTEK- 2016NT08198384F4

### Prepared for

Ingram Micro Chile S.A El Rosal,4765,Huechuraba,Santiago,CL

### Prepared by

Shenzhen NTEK Testing Technology Co., Ltd.

1/F, Building E, Fenda Science Park, Sanwei Community, Xixiang Street Bao'an District, Shenzhen 518126 P.R. China

Tel.: +86-755-6115 6588 Fax.: +86-755-6115 6599 Website:http://www.ntek.org.cn Applicant's name .....: Ingram Micro Chile S.A



# TEST RESULT CERTIFICATION

Report No.: NTEK-2016NT08198384F4

Address:	El Rosal,4765,Huechuraba,Santiago,CL				
Manufacturer's Name:	Haier International (HK) Limited				
ΔΛΛΙΔΘΕ	503,Block B2, KeXing Science Park, KeYuan Road, Nanshan, Shenzhen, China				
Product description					
Product name:	Smartphone				
Model and/or type reference :	N/A				
Standards:	FCC Part15B: 21 Sep.2016 ANSI C63.4:2014				
	s been tested by NTEK, and the test results show that the compliance with Part 15 of FCC Rules. And it is applicable only to be report.				
·	ced except in full, without the written approval of NTEK, this ised by NTEK, personnel only, and shall be noted in the revision of				
Date (s) of performance of tests.	: 19 Aug. 2016 ~ 26Sep. 2016				
Date of Issue					
Test Result					
Testing Engine	eer : <u>Eileen Wu.</u> (Eileen Liu)				
<del>-</del>	Jason chen				
Technical Mana	ager : (Jason Chen)				
Authorized Sign	(Sam Chen)				
	(Sam Chen)				



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1. TEST SUMMARY

Test procedures according to the technical standards:

EMC Emission							
Standard	Test Item	Limit	Judgment	Remark			
FCC Part15B:2016 ANSI C63.4: 2014	Conducted Emission	Class B	PASS				
	Radiated Emission	Class B	PASS				

# NOTE:

- (1) 'N/A' denotes test is not applicable in this Test Report
- (2) For client's request and manual description, the test will not be executed.



### 1.1 TEST FACILITY

ShenZhen NTEK Testing Technology Co., Ltd

Add.: 1/F, Building E, Fenda Science Park, Sanwei Community, Xixiang Street, Bao'an District, Shenzhen P.R. China.

FCC Registration Number:238937; IC Registration Number:9270A-1

CNAS Registration Number:L5516

### 1.2 MEASUREMENT UNCERTAINTY

The reported uncertainty of measurement  $\mathbf{y} \pm \mathbf{U}$ , where expended uncertainty  $\mathbf{U}$  is based on a standard uncertainty multiplied by a coverage factor of  $\mathbf{k=2}$ , providing a level of confidence of approximately 95 %.

### A. Conducted Measurement:

Test Site	Method	Measurement Frequency Range	U, (dB)	NOTE
NTEKC01	ANSI	150 KHz ~ 30MHz	3.2	

### B. Radiated Measurement:

Test Site	Method	Measurement Frequency Range	U, (dB)	NOTE
NTEKA01	ANSI	30MHz ~ 1000MHz	4.7	
		1GHz ~12.4GHz	5.0	



# 2. GENERAL INFORMATION

# 2.1 GENERAL DESCRIPTION OF EUT

Equipment	Smartphone					
Trade Name	OWN					
Model Name	One Glass					
Serial Model	N/A					
Model Difference	N/A	N/A				
	The EUT is a Industria	al Smartphone.				
Product Description	Connecting I/O port:  Operation Frequency:  B Frequency:  V V V G G I I I I I I I I I I I I I I	ISB, Earphone  IT(BLE):2402~2480MHz IT(BR+EDR): 2402~2480MHz IT(BR+EDR): 2402~2480MHz IT(BR+EDR): 2402~2452MHz; ITE 802.11 N40:2422~2452MHz; ISM850: TX824.2MHz~848.8MHz IXX869.2MHz~893.8MHz; IXX869.2MHz~893.8MHz; IXX1930.2MHz~1989.8MHz; IXX1930.2MHz~1989.8MHz; IXX1932.4MHz~1987.6MHz; IXX1932.4MHz~1987.6MHz; IXX1932.4MHz~1987.6MHz; IXX869MHz~894MHz; ITE FDD Band 2 Uplink: 1850.7MHz-1909.3MHz, IXX869MHz~894MHz; ITE FDD Band 4 Uplink: 1710MHz-1755MHz, IXX869MHz-2155MHz IXIN 1930.7MHz-1989.3MHz: IXIN 1930.7MHz-2155MHz IXIN 1930.7MHz IXIN 1930.7				
	D IE (() G V	PSSS (CCK, QPSK, DBPSK) EEE 802.11g/n (HT20/HT40) : OFDM E4QAM, 16QAM, QPSK, BPSK) ESM / DCS: GMSK PCDMA:QPSK EGPRS: 8PSK TE: QPSK/16QAM				
Power Source	DC 3.8V/2050mAh from	m Battery or DC 5V from Adapter.				
	Model:HJ-0501000E1-	US				
Adapter	Input:AC 100~240V 50	/60Hz 0.2A				
	Output:DC 5V,1000mA	.h				
Battery	DC 3.8V, 2050mAh					



### 2.1.1 DESCRIPTION OF TEST MODES

To investigate the maximum EMI emission characteristics generates from EUT, the test system was pre-scanning tested base on the consideration of following EUT operation mode or test configuration mode which possible have effect on EMI emission level. Each of these EUT operation mode(s) or test configuration mode(s) mentioned above was evaluated respectively.

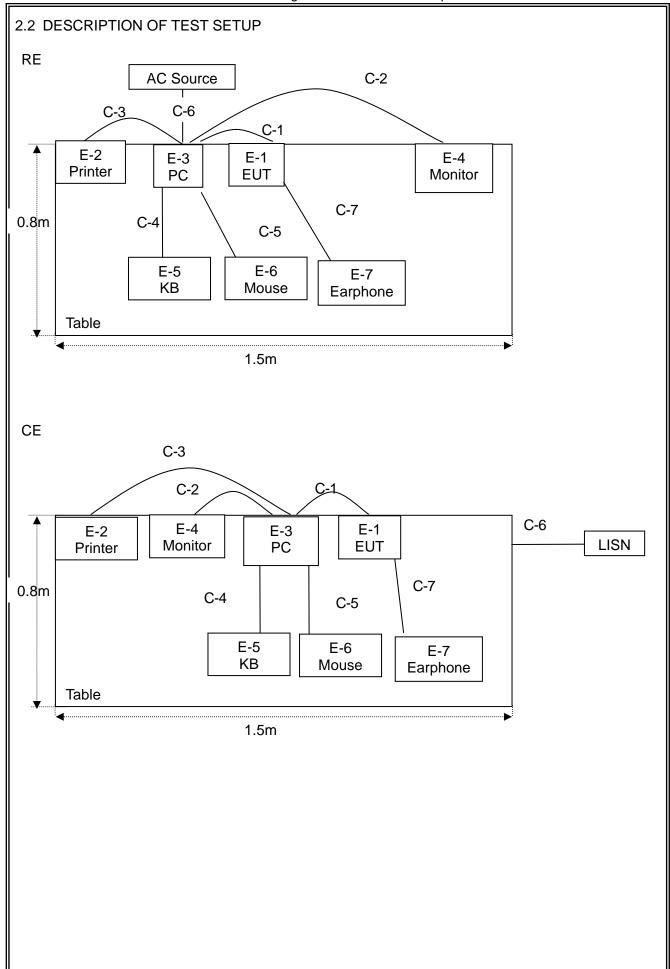
Pretest Mode	Description
Mode 1	Connect to PC
Mode 2	Camera
Mode 3	TF card Play
Mode 4	"H" Pattern

For Conducted Test			
Final Test Mode	Description		
Mode 1	Connect to PC		
Mode 2	Camera		
Mode 3	TF card Play		
Mode 4	"H" Pattern		

For Radiated Test			
Final Test Mode	Description		
Mode 1	Connect to PC		
Mode 2	Camera		
Mode 3	TF card Play		
Mode 4	"H" Pattern		

Note: Final Test Mode: Through Pre-scan, find the mode 1 is the worst case. Only the worst case mode is recorded in the report.







### 2.3 DESCRIPTION TEST PERIPHERAL AND EUT PERIPHERAL

The EUT has been tested as an independent unit together with other necessary accessories or support units. The following support units or accessories were used to form a representative test configuration during the tests.

Item	Equipment	Brand	Model/Type No.	Series No.	Note
E-1	Smartphone	OWN	One Glass	N/A	EUT
E-2	Printer	Canon	L11121E	LBP2900	
E-3	Personal computer	DELL	FT4Y23X	34413561645	
E-4	Monitor	DELL	IN2020MB	cn-0y6mhx-74261-11f-67e s	
E-5	Keyboard	DELL	SK-8185	OY526KUS	
E-6	Mouse	DELL	MS111-P	cn-011d3v-71581-11e-1th7	
E-7	Earphone	N/A	L662	N/A	

Item	Cable Type	Shielded Type	Ferrite Core	Length	Note
C-1	USB Cable	unshielded	NO	1.2m	
C-2	VGA	unshielded	NO	1.0m	
C-3	USB Cable	unshielded	NO	1.2m	
C-4	USB Cable	unshielded	NO	1.0m	
C-5	USB Cable	unshielded	NO	1.0m	
C-6	Power Line	unshielded	NO	1.2m	
C-7	Earphone Cable	unshielded	Yes	1.0m	

### Note:

- (1) The support equipment was authorized by Declaration of Confirmation.
- (2) For detachable type I/O cable should be specified the length in cm in <code>"Length\_"</code> column.
- (3) "YES" means "shielded" "with core"; "NO" means "unshielded" "without core".



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# 2.4 MEASUREMENT INSTRUMENTS LIST

Radiation Test equipment

Item		Manufacturer	Type No.	Serial No.	Last	Calibrated	Calibratio
4	Equipment			NA)/4540004	calibration	until	n period
1	Spectrum Analyzer	Agilent	E4407B	MY4510804 0	2016.07.06	2017.07.05	1 year
2	Test Receiver	R&S	ESPI	101318	2016.06.07	2017.06.06	1 year
3	Bilog Antenna	TESEQ	CBL6111D	31216	2016.07.06	2017.07.05	1 year
4	50Ω Coaxial Switch	Anritsu	MP59B	620026441 6	2016.06.07	2017.06.06	1 year
5	Spectrum Analyzer	ADVANTEST	R3132	150900201	2016.06.07	2017.06.06	1 year
6	Horn Antenna	EM	EM-AH-101 80	2011071402	2016.07.06	2017.07.05	1 year
7	Horn Ant	Schwarzbeck	BBHA 9170	9170-181	2016.07.06	2017.07.05	1 year
8	Amplifier	EM	EM-30180	060538	2015.12.22	2016.12.21	1 year
9	Loop Antenna	ARA	PLA-1030/B	1029	2016.06.08	2017.06.07	1 year
10	Power Meter	R&S	NRVS	100696	2016.07.06	2017.07.05	1 year
11	Power Sensor	R&S	URV5-Z4	0395.1619. 05	2016.07.06	2017.07.05	1 year
12	Test Cable	N/A	R-01	N/A	2016.07.06	2017.07.05	1 year
13	Test Cable	N/A	R-02	N/A	2016.07.06	2017.07.05	1 year

# Conduction Test equipment

Item	Kind of Equipment	Manufactu rer	Type No.	Serial No.	Last calibration	Calibrated until	Calibratio n period
1	Test Receiver	R&S	ESCI	101160	2016.07.06	2017.07.05	1 year
2	LISN	R&S	ENV216	101313	2016.08.24	2017.08.23	1 year
3	LISN	EMCO	3816/2	00042990	2016.08.24	2017.08.23	1 year
4	50Ω Coaxial Switch	Anritsu	MP59B	620026441 7	2016.06.07	2017.06.06	1 year
5	Passive Voltage Probe	R&S	ESH2-Z3	100196	2016.06.07	2017.06.06	1 year
6	Absorbing clamp	R&S	MOS-21	100423	2016.06.08	2017.06.07	1 year
7	Test Cable	N/A	C01	N/A	2016.06.08	2017.06.07	1 year
8	Test Cable	N/A	C02	N/A	2016.06.08	2017.06.07	1 year
9	Test Cable	N/A	C03	N/A	2016.06.08	2017.06.07	1 year



### 3. EMC EMISSION TEST

### 3.1 CONDUCTED EMISSION MEASUREMENT

# 3.1.1 POWER LINE CONDUCTED EMISSION (Frequency Range 150KHz-30MHz)

FREQUENCY (MHz)	Class A	(dBuV)	Class B (dBuV)		
FREQUENCY (MHZ)	Quasi-peak	Average	Quasi-peak	Average	
0.15 -0.5	79.00	66.00	66 - 56 *	56 - 46 *	
0.50 -5.0	73.00	60.00	56.00	46.00	
5.0 -30.0	73.00	60.00	60.00	50.00	

### Note:

- (1) The tighter limit applies at the band edges.
- (2) The limit of " \* " marked band means the limitation decreases linearly with the logarithm of the frequency in the range.

The following table is the setting of the receiver

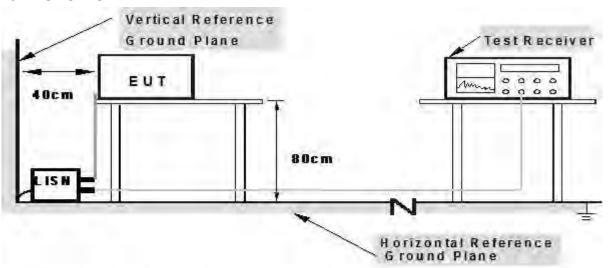
Receiver Parameters	Setting
Attenuation	10 dB
Start Frequency	0.15 MHz
Stop Frequency	30 MHz
IF Bandwidth	9 kHz



### 3.1.2 TEST PROCEDURE

- a. The EUT was placed 0.8 meters from the horizontal ground plane with EUT being connected to the power mains through a line impedance stabilization network (LISN). All other support equipments powered from additional LISN(s). The LISN provide 50 Ohm/ 50uH of coupling impedance for the measuring instrument.
- b. Interconnecting cables that hang closer than 40 cm to the ground plane shall be folded back and forth in the center forming a bundle 30 to 40 cm long.
- c. I/O cables that are not connected to a peripheral shall be bundled in the center. The end of the cable may be terminated, if required, using the correct terminating impedance. The overall length shall not exceed 1 m.
- d LISN at least 80 cm from nearest part of EUT chassis.
- e For the actual test configuration, please refer to the related Item –EUT Test Photos.

### 3.1.3 TEST SETUP



Note: 1. Support units were connected to second LISM. 2.Both of LISNs (AMN) are 80 cm from EUT and at least 80 from other units and other metal planes

### 3.1.4 EUT OPERATING CONDITIONS

The EUT tested system was configured as the statements of 2.3 Unless otherwise a special operating condition is specified in the follows during the testing.

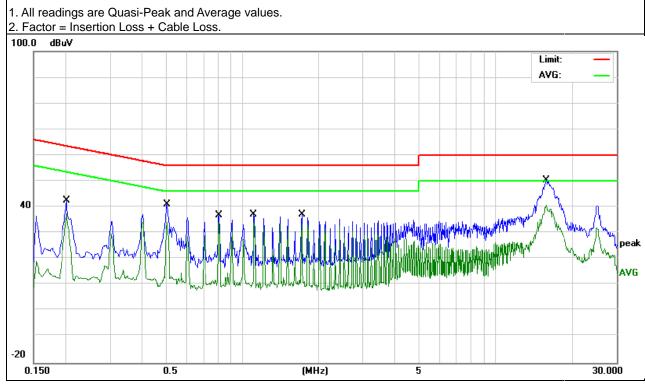


# 3.1.5 TEST RESULTS

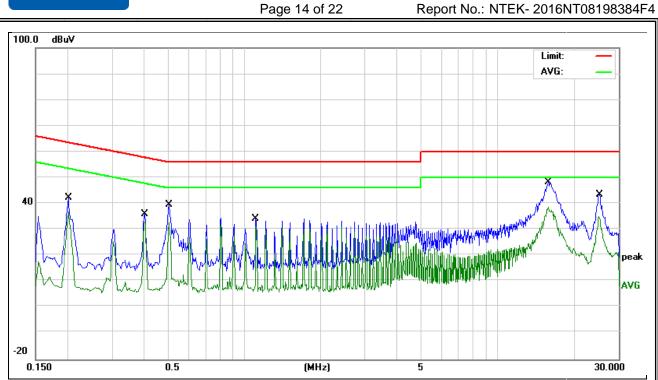
EUT:	Smartphone	Model Name. :	One Glass		
Temperature:	26 ℃	Relative Humidity:	54%		
Pressure:	1010hPa	Test Date:	2016-8-19		
Test Mode:	Mode 1	Phase :	L		
Test Voltage:	DC 5V From Adapter AC 120V/60Hz				

Frequency	Reading Level	Correct Factor	Measure-ment	Limits	Margin	Remark
(MHz)	(dBµV)	(dB)	(dBµV)	(dBµV)	(dB)	Remark
0.2020	32.51	10.13	42.64	63.52	-20.88	QP
0.2020	27.32	10.13	37.45	53.52	-16.07	AVG
0.5060	31.19	9.81	41.00	56.00	-15.00	QP
0.5060	24.33	9.81	34.14	46.00	-11.86	AVG
0.8100	27.11	9.82	36.93	56.00	-19.07	QP
0.8100	24.42	9.82	34.24	46.00	-11.76	AVG
1.1100	27.26	9.86	37.12	56.00	-18.88	QP
1.1100	24.18	9.86	34.04	46.00	-11.96	AVG
1.7177	27.31	9.79	37.10	56.00	-18.90	QP
1.7177	23.53	9.79	33.32	46.00	-12.68	AVG

### Remark:







Phase:



Temperature: Pressure:

Test Mode:

EUT:

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	Model Name. :	One Glass			
	Relative Humidity:	54%			
	Test Date:	2016-8-19			

Test Voltage:	DC 5V From Adapter	· AC	120V/60Hz
TOOL VOILAGE.		, , ,	120 1/001 12

Smartphone

**26** ℃

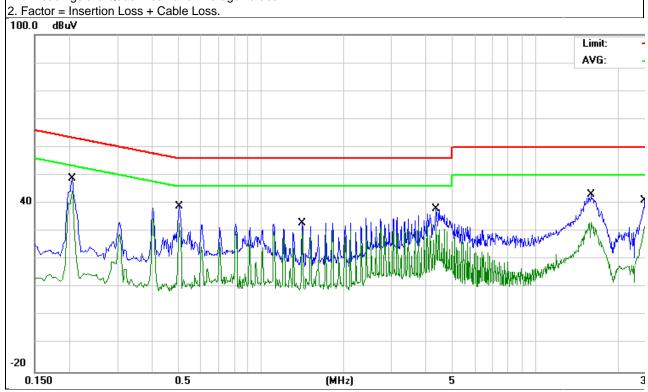
1010hPa

Mode 1

Frequency	Reading Level	Correct Factor	Measure-ment	Limits	Margin	Remark
(MHz)	(dBµV)	(dB)	(dBµV)	(dBµV)	(dB)	Remark
0.2058	38.69	10.03	48.72	63.37	-14.65	QP
0.2058	34.32	10.03	44.35	53.37	-9.02	AVG
0.5060	29.06	9.83	38.89	56.00	-17.11	QP
0.5060	23.12	9.83	32.95	46.00	-13.05	AVG
1.4174	23.12	9.84	32.96	56.00	-23.04	QP
1.4174	20.45	9.84	30.29	46.00	-15.71	AVG
4.3578	28.21	9.78	37.99	56.00	-18.01	QP
4.3578	22.47	9.78	32.25	46.00	-13.75	AVG
15.8939	33.09	9.95	43.04	60.00	-16.96	QP
15.8939	23.25	9.95	33.20	50.00	-16.80	AVG

### Remark:

1. All readings are Quasi-Peak and Average values.





### B.1.6 RADIATED EMISSION MEASUREMENT

### 3.1.7 LIMITS OF RADIATED EMISSION MEASUREMENT

FREQUENCY (MHz)	Class A (at 10m)	Class B (at 3m)	
PREQUENCY (MINZ)	dBuV/m	dBuV/m	
30 ~ 88	39.0	40.0	
88 ~ 216	43.5	43.5	
216 ~ 960	46.5	46.0	
Above 960	49.5	54.0	

### Notes:

- (1) The limit for radiated test was performed according to as following: FCC PART 15B /ICES-003.
- (2) The tighter limit applies at the band edges.
- (3) Emission level (dBuV/m)=20log Emission level (uV/m).

### 3.1.8 TEST PROCEDURE

### Test Arrangement for Radiated Emissions up to 1 GHz

- a. The EUT was placed on the top of a rotating table 0.8 meters above the ground at ar accredited test facility. The table was rotated 360 degrees to determine the position of the highest radiation.
- b. The EUT was set 3 meters away from the interference-receiving antenna, which was mounted on the top of a variable-height antenna tower.
- c. The antenna is a broadband antenna, and its height is varied from one meter to four meters above the ground to determine the maximum value of the field strength. Both horizontal and vertical polarizations of the antenna are set to make the measurement.
- d. For each suspected emission, the EUT was arranged to its worst case and then the antenna was tuned to heights from 1 meter to 4 meters and the rotatable table was turned from ( degrees to 360 degrees to find the maximum reading.

Note: The resolution bandwidth and video bandwidth of test receiver/spectrum analyzer is 120kHz for quasi-peak detection (QP) at frequency below 1GHz.

### Test Arrangement for Radiated Emissions above 1 GHz.

- a. The EUT was placed on the top of a rotating table 0.8 meters above the ground at an accredited chamber room. The table was rotated 360 degrees to determine the position of the highest radiation.
- b. The EUT was set 3 meters away from the interference-receiving antenna, which was mounted on the top of a variable-height antenna tower.
- c. The height of antenna can be varied from one meter to four meters, the height of adjustment depends on the EUT height and the antenna 3dB beamwidth both, to detect the maximum value of the field strength. Both horizontal and vertical polarizations of the antenna are set to make the measurement.
- d. For each suspected emission, the EUT was arranged to its worst case and then the antenna was tuned to heights and the rotatable table was turned from 0 degrees to 360 degrees to find the maximum reading.

Note: For the hand-held device, the EUT should be measured for all 3 axes and only the worst



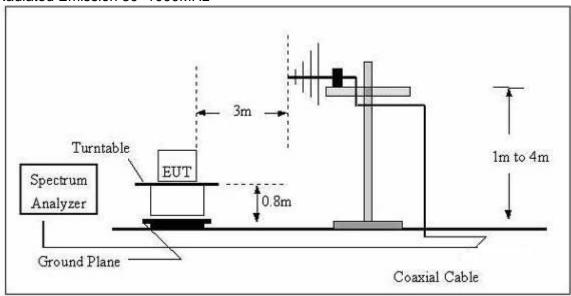
case is recorded in the report

During the radiated emission test, the Spectrum Analyzer was set with the following configurations:

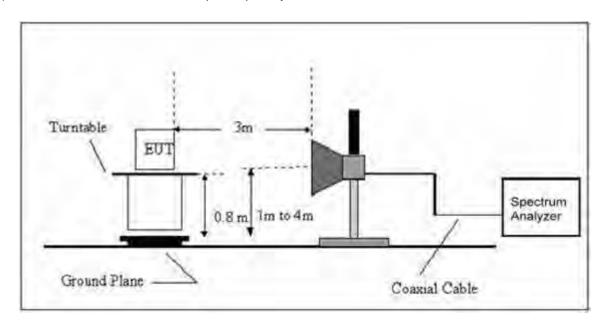
Frequency Band (MHz)	Function	Resolution bandwidth	Video Bandwidth
30 to 1000	QP	120 kHz	300 kHz
	Peak	1 MHz	1 MHz
Above 1000	Avg	1 MHz	10 Hz

### 3.1.9 TEST SETUP

For Radiated Emission 30~1000MHz



# (B) Radiated Emission Test Set-Up Frequency Above 1GHz





# 3.1.10 TEST RESULTS

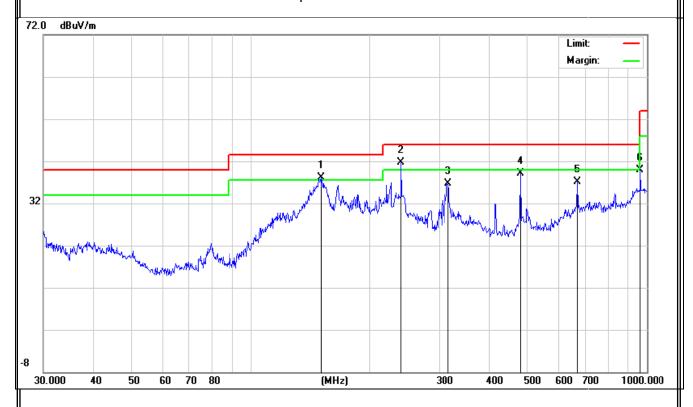
# TEST RESULTS (30~1000 MHz)

EUT:	Smartphone	Model Name.:	One Glass		
Temperature:	<b>24</b> °C	Relative Humidity:	54%		
Pressure:	1010 hPa	Test Date :	2016-8-19		
Test Mode:	Mode 1	Polarization:	Horizontal		
Test Power :	DC 5V From Adapter AC 120V/60Hz				

Polar	Frequency	Meter Reading	Factor	Emission Level	Limits	Margin	Remark
(H/V)	(MHz)	(dBuV)	(dB)	(dBuV/m)	(dBuV/m)	(dB)	Kornark
Н	150.5378	25.24	12.84	38.08	43.50	-5.42	QP
Н	239.9874	29.71	11.96	41.67	46.00	-4.33	QP
Н	315.4806	22.23	14.38	36.61	46.00	-9.39	QP
Н	480.5276	21.17	17.92	39.09	46.00	-6.91	QP
Н	668.1422	15.10	22.06	37.16	46.00	-8.84	QP
Н	962.1621	11.87	28.13	40.00	54.00	-14.00	QP

### Remark:

Factor = Antenna Factor + Cable Loss - Amplifier.





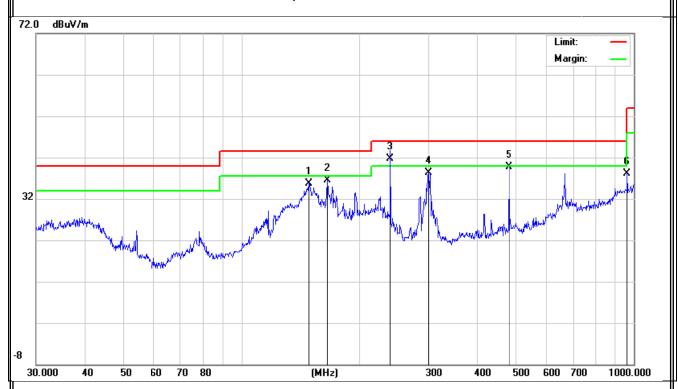
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EUT:	Smartphone	Model Name.:	One Glass	
Temperature:	24 ℃	Relative Humidity:	54%	
Pressure:	1010 hPa	Test Date :	2016-8-19	
Test Mode:	Mode 1	Polarization:	Vertical	
Test Power:	DC 5V From Adapter AC 120V/60Hz			

Polar (H/V)	Frequency	Meter Reading	Factor	Emission Level	Limits	Margin	Remark
	(MHz)	(dBuV)	(dB)	(dBuV/m)	(dBuV/m)	(dB)	
V	148.4410	23.03	12.69	35.72	43.50	-7.78	QP
V	165.4866	23.65	12.87	36.52	43.50	-6.98	QP QP QP QP QP QP
V	239.9874	29.84	11.96	41.80	46.00	-4.20	QP
V	300.3672	24.47	13.84	38.31	46.00	-7.69	QP
V	480.5276	21.77	17.92	39.69	46.00	-6.31	QP
V	962.1621	9.96	28.13	38.09	54.00	-15.91	QP

Remark:

Factor = Antenna Factor + Cable Loss - Amplifier.





# 3.1.11 TEST RESULTS(1000~12400MHz)

Polar (H/V)	Frequency	Meter Reading	Factor	Emission Level	Limits	Margin	Remark	
	(MHz)	(dBuV)	(dB)	(dBuV/m)	(dBuV/m)	(dB)		
V	1093.724	44.67	-12.05	32.62	74.00	-41.38	peak	
V	1093.724	34.95	-12.05	22.90	54.00	-31.10	AVG	
V	2401.684	43.54	-5.23	38.31	74.00	-35.69	peak	
V	2401.684	33.63	-5.23	28.40	54.00	-25.60	AVG	
V	2626.779	41.01	-4.52	36.49	74.00	-37.51	peak	
V	2626.779	30.12	-4.52	25.60	54.00	-28.40	AVG	
Н	1438.681	45.80	-10.06	35.74	74.00	-38.26	peak	
Н	1438.681	34.56	-10.06	24.50	54.00	-29.50	AVG	
Н	2631.490	40.40	-4.54	35.86	74.00	-38.14	peak	
Н	2631.490	29.64	-4.54	25.10	54.00	-28.90	AVG	
Н	5226.773	35.16	3.68	38.84	74.00	-35.16	peak	
Н	5226.773	24.12	3.68	27.80	54.00	-26.20	AVG	
Domonile:								

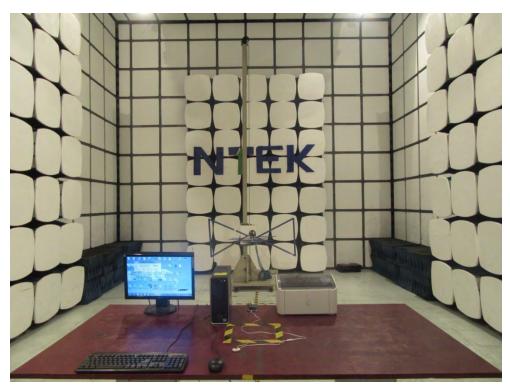
Remark:

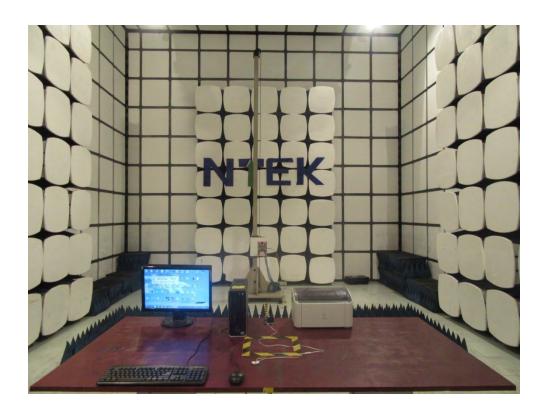
Absolute Level= ReadingLevel+ Factor, Margin= Absolute Level - Limit



# 4. EUT TEST PHOTO











# **Conducted Measurement Photos**

